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L4	512	L3 same imag$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
L5	217	(382/106).CCLS.	US-PGPUB; USPAT; USOCR; IBM_TDB	OR	OFF	2005/04/01 14:35
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L8	5	L7 same (during time while)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S1	1548	imag$4 same coordinat$4 same sens$4 same displa$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:05
S2	103	S1 same displac$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S3	30	S2 same time	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:09
S4	6011	displac$4 near4 sens$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:10
S5	481	S4 same imag$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35
S6	21	S5 same coordinat$4	US-PGPUB; USPAT; IBM_TDB	OR	ON	2004/09/14 14:10
S7	5	S6 same (during time while)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2005/04/01 14:35

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